

TIPP 2011: a few highlights...

Conference venue



Devis Contarato

Brown Bag Instrumentation talk

June 21, 2011



BERKELEY LAB

Lawrence Berkeley National Laboratory

Notes

- I attended only the first 3 days of the conference, therefore my take comes from a limited perspective...
- 9 parallel tracks at the conference, I hopped between:
 - Semiconductor detectors
 - Front-end electronics
 - Instrumentation for biological, medical and material research
- My 5 picks, somehow exotic:
 - One plenary talk on the future of CMOS and High-Performance Computing
 - A couple technologies alternative to Si-planar sensors (3D sensors, diamond)
 - A couple examples of X-ray detectors (SOI, DEPFET for XFEL)

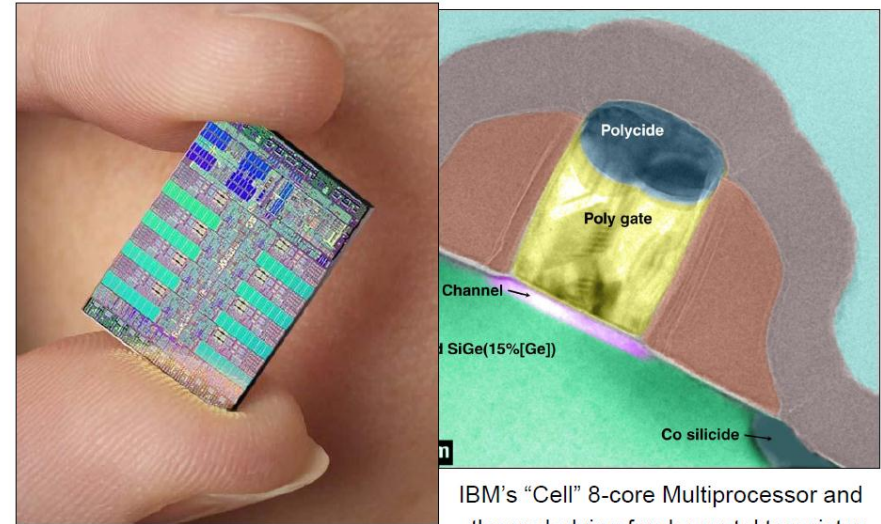
Beyond CMOS

The Engine Driving The Digital Age

K. Bernstein- IBM TJ Watson Research Center

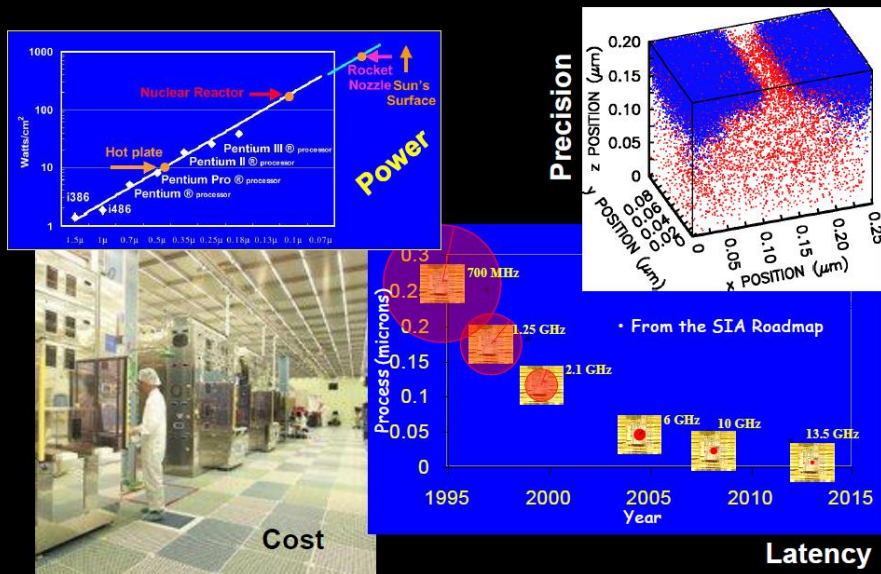
"The Evolution of CMOS and post-CMOS Electronics", plenary talk

- Despite the advances in technology and miniaturization, the basic building block of modern microprocessors is still... a binary switch!
- As the technology node scales down, CMOS processes are facing fundamental limitations, which will soon become quantum mechanical...

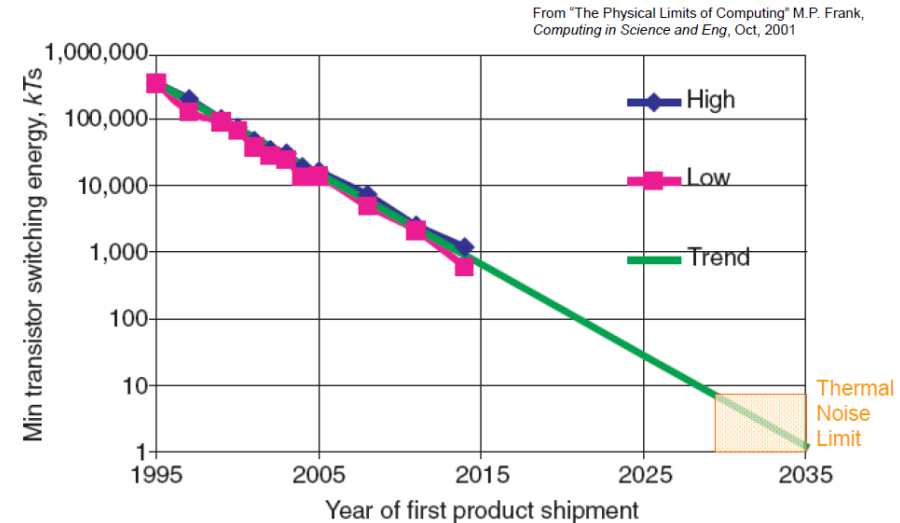


IBM's "Cell" 8-core Multiprocessor and the underlying fundamental transistor

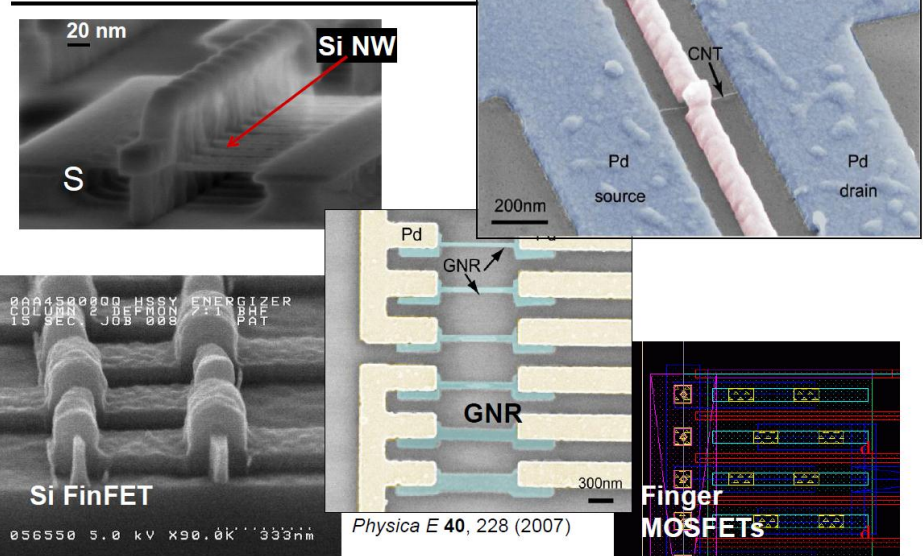
Limits to the Present Technology



Ultimate Boundaries: Minimum Switching Energy



Logic at the Unit Gate Level



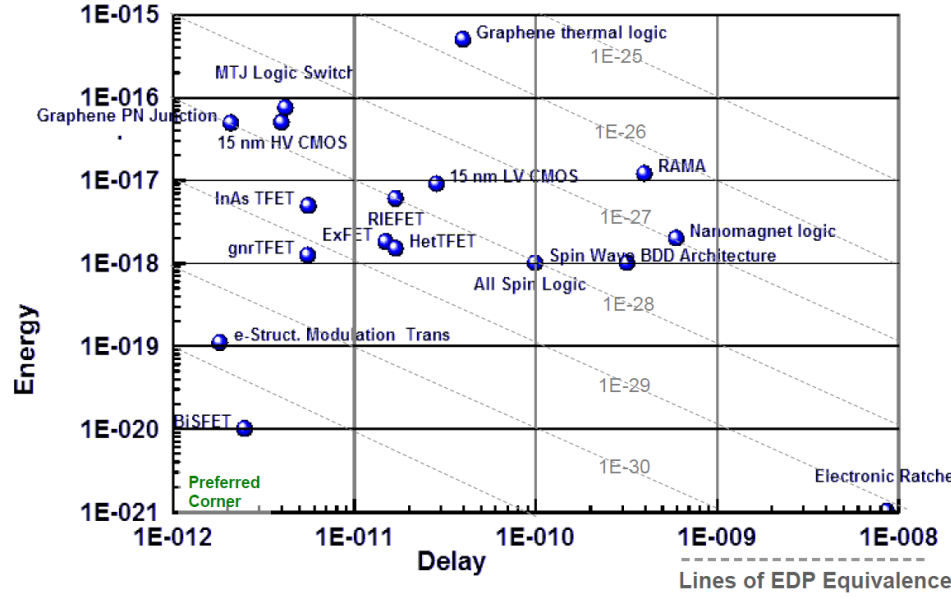
- There is a wealth of research towards the beyond-CMOS switch (not necessarily binary), involving nanotechnology and such...

Switches going forward naturally quantize their output – can we exploit this in new architectures?

- ... but the challenge is still about keeping up with speed demands at low power consumption!

NAND2 Delay vs Energy

Raw Data

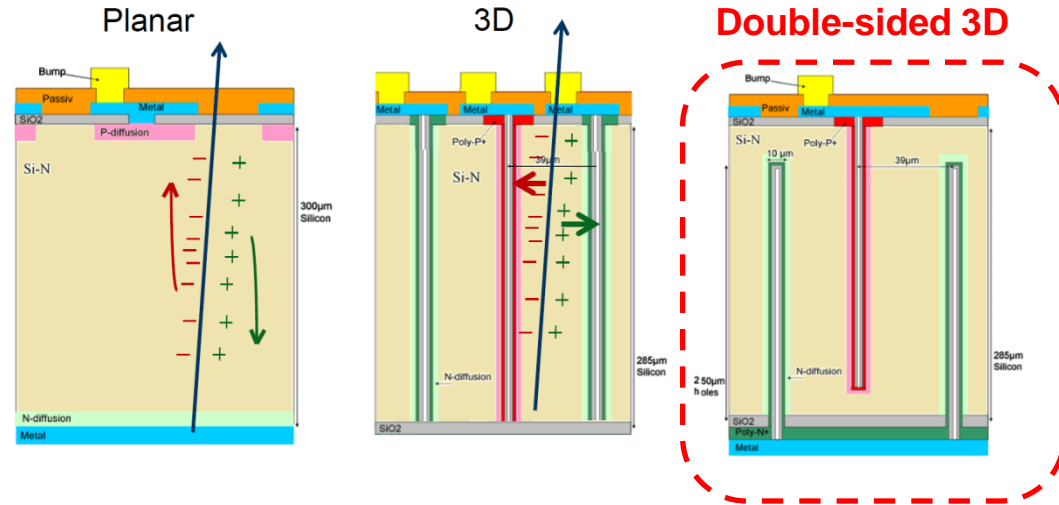


A potential Delay-Energy minima exists at approximately 1E-29

3D silicon sensors

A. Mac Raighne – University of Glasgow
 “Characterisation of Glasgow/CNM double-sided 3D sensors”

- Electrodes are “pillars” implanted in sensor substrate: lateral depletion, lower depletion voltage, faster collection time → less trapping, more rad-hard...
- ... but: complex process, yield issues, areas of inefficiency
- Double-sided approach has easier fabrication process (?), minimizes inefficiency regions
- Best performance in beam-test obtained with detector at an angle



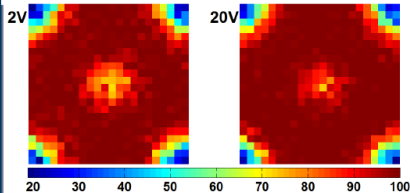
Beam test on 3D n-type pixel sensor, 55 µm pitch



Precision scans: Efficiency

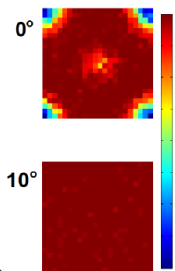
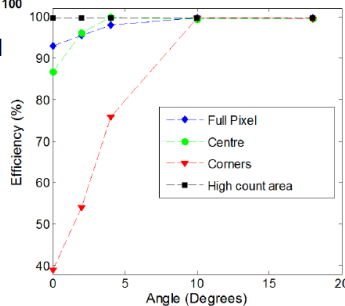
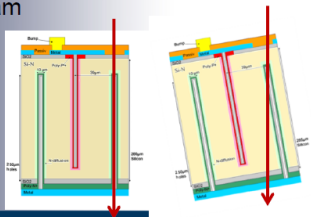
Timepix Telescope

120 GeV π , w/ reference telescope



Voltage	Corner	Centre	Ring	Pixel
2V	35.6	79.1	99.1	91.2
20V	39.1	86.7	99.7	93.0

Full efficiency, $99.8 \pm 0.5\%$, reached at an angle of 10° to the incident beam

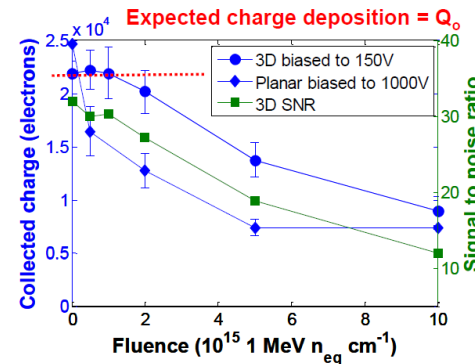
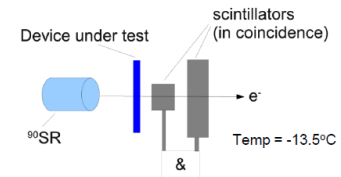


Charge collection efficiencies (150V)

Sr-90 electrons

^{90}Sr source, after $10^{16} \text{ n}_{\text{eq}} \text{ cm}^{-2}$

- Large charge collection at high fluences and modest voltages
- 3D charge collection of 47% of Q_0 @ 10^{16} fluence at 150V
- This has been simulated using TCAD without any high field effects present and shows very good agreement
- Noise is constant giving a signal to noise value of >10 @ 10^{16} fluence at 150V
- Compared to planar sensor higher charge collected
- Planar charge collection, 30% of Q_0 @ 10^{16} fluence at 1000V



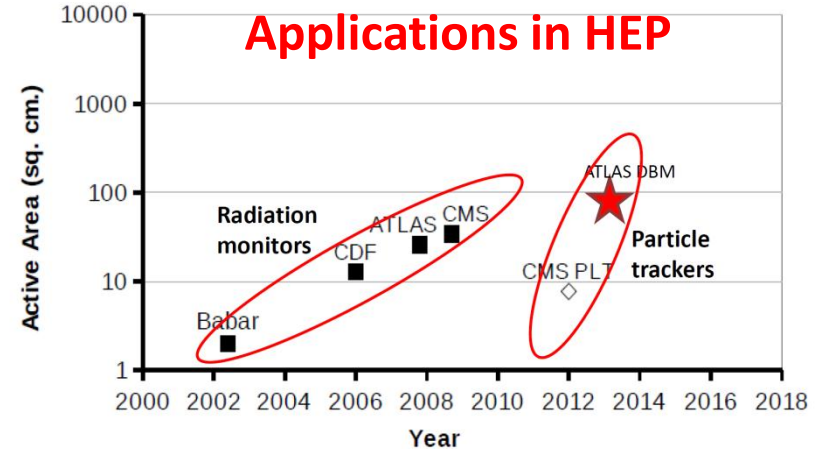
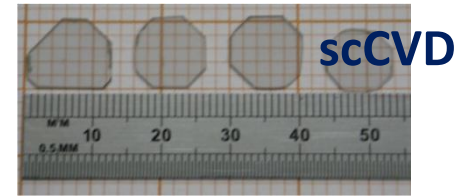
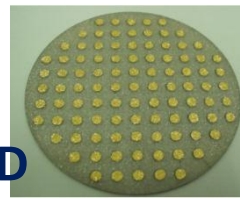
Diamond detectors

M. Mikuz – University of Ljubljana & Josef Stefan Institute
For the RD42 Collaboration

“Diamond Sensors for High Energy Radiation and Particle Detection”

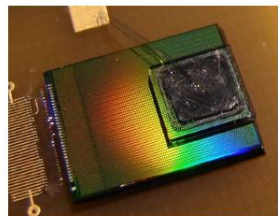
- With respect to silicon, diamond shows lower leakage, higher mobility (faster signals), and is more radiation-hard
- Two sensor types:
 - polycrystalline (pCVD), exists in 12 cm wafer
 - single crystal (scCVD), exists only in $\sim\text{cm}^2$ pieces
- All LHC experiments use diamond as beam monitors
- Proposed trackers:
 - CMS Pixel Luminosity Telescope (PLT)
 - ATLAS Diamond Beam Monitor (DBM)

pCVD

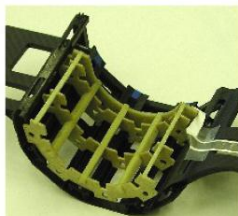


CMS Pixel Luminosity Telescope

- Dedicated, stand-alone luminosity monitor
 - Eight 3-plane telescopes each end of CMS
 - 1.60° pointing angle $r = 4.8\text{ cm}$, $z = 175\text{ cm}$
- Diamond pixel sensors active area:
 - $3.9\text{ mm} \times 3.9\text{ mm}$, scCVD diamond
- Count 3-fold coincidences fast-or signals (40 MHz)
- Full pixel readout pixel address, pulse height (1 kHz)
- Stable 1% precision on bunch-by-bunch relative luminosity



PLT plane



Cassette for 12 planes

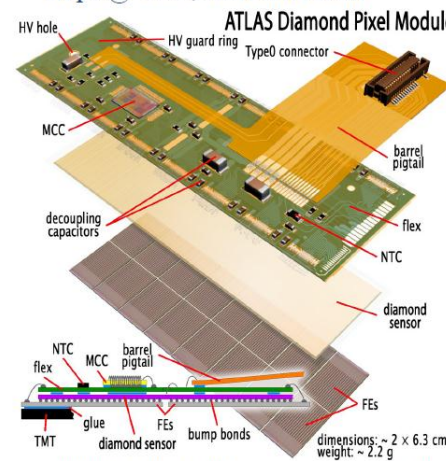


Full cassette in test-beam



Diamond pixel modules

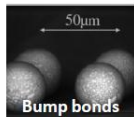
- Full modules built with I3 pixel chips @ OSU, IZM and Bonn



Pattern with In bumps



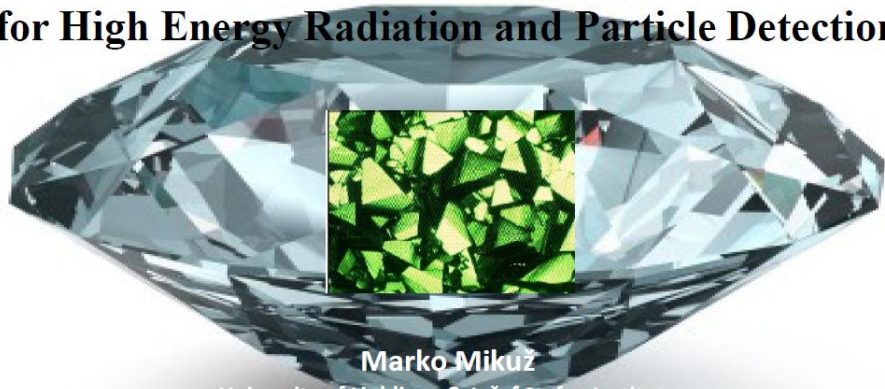
Edgeless scCVD module pattern



Bump bonds

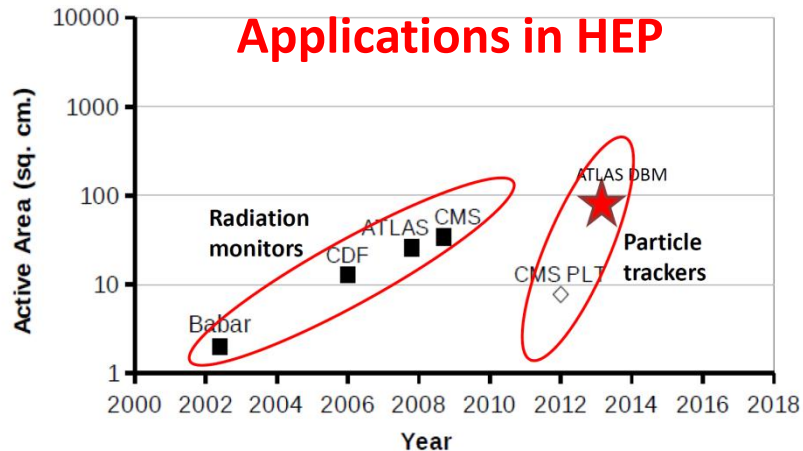
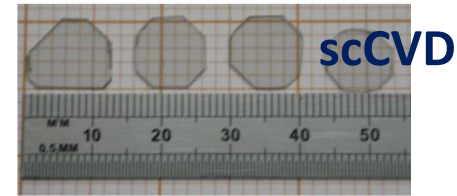
Diamond Sensors

for High Energy Radiation and Particle Detection



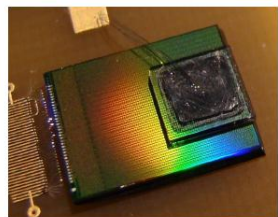
Marko Mikuž
University of Ljubljana & Jožef Stefan Institute
Ljubljana, Slovenia
for the CERN RD-42 Collaboration

TIPP 2011
Chicago, IL, USA
June 9-14, 2011

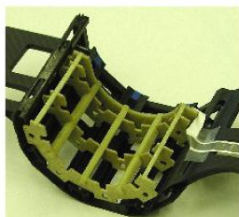


CMS Pixel Luminosity Telescope

- Dedicated, stand-alone luminosity monitor
 - Eight 3-plane telescopes each end of CMS
 - 1.60° pointing angle $r = 4.8$ cm, $z = 175$ cm
- Diamond pixel sensors active area:
 - 3.9 mm x 3.9 mm, scCVD diamond
- Count 3-fold coincidences fast-or signals (40 MHz)
- Full pixel readout pixel address, pulse height (1 kHz)
- Stable 1% precision on bunch-by-bunch relative luminosity



PLT plane



Cassette for 12 planes

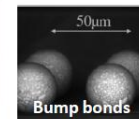
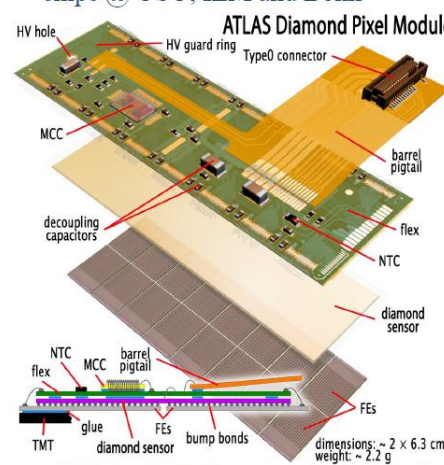


Full cassette in test-beam



Diamond pixel modules

- Full modules built with I3 pixel chips @ OSU, IZM and Bonn



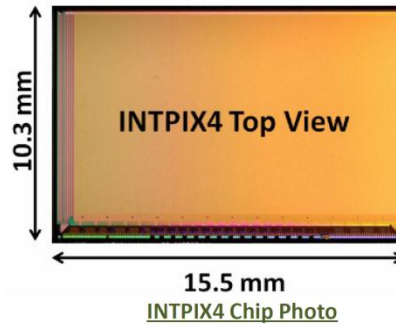
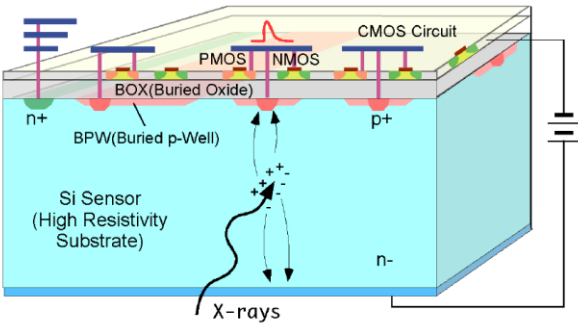
SOI pixels for X-rays

A. Takeda - KEK

“High resolution X-ray Imaging Sensor with SOI CMOS technology”

- Monolithic detector that integrates full CMOS electronics on a high-resistivity, fully-depleted substrate, no bump-bonding
- ½-reticle size imager, 17 μm pitch pixel with Correlated Double-Sampling (CDS)
- 260 μm thick, fully-depleted substrate, back-illuminated
- Test with X-rays at various energies, energy resolution improves with cooling
- ... we are working on similar developments here at LBNL!

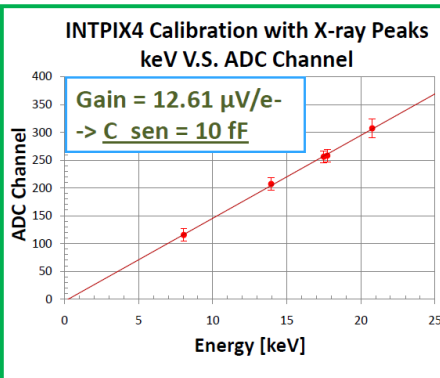
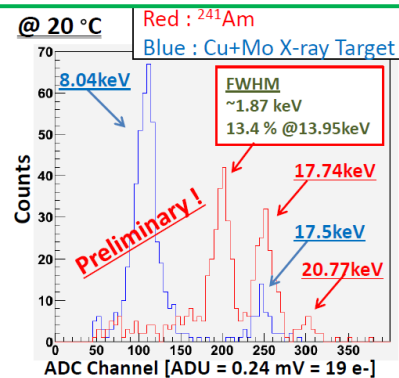
SOI Pixel Detector



Energy Resolution

- Energy Spectrum @Room Temp.
 - ²⁴¹Am and Cu + Mo X-ray Target
- **FWHM : 13.4 % @ 13.95 keV**
- **Sensor Capacitor : 10 fF**

V sensor = 200 V
Integration Time = 250 μs
Back-illumination



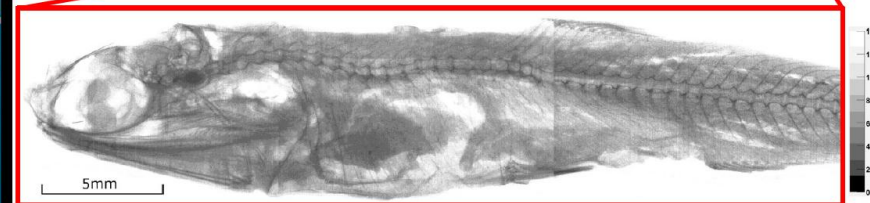
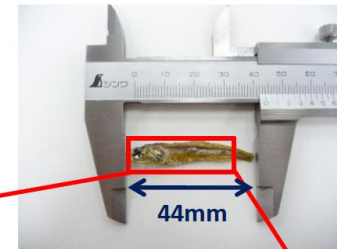
INTPIX4 X-ray Imaging

20 keV X-rays
room T, V_{dep} = 200 V

- **Fine Resolution & High Contrast !**

250 μs Int. x 500 fr

- * It is clear even by 100 fr.
- ** It depends on the number of photons.



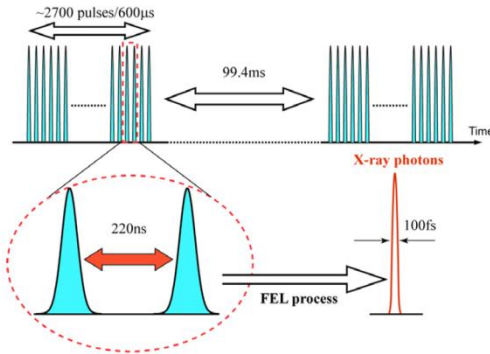
X-ray Imaging of a small dried sardine taken by an INTPIX4 (3 images are combined).

DEPFETs for EU-XFEL

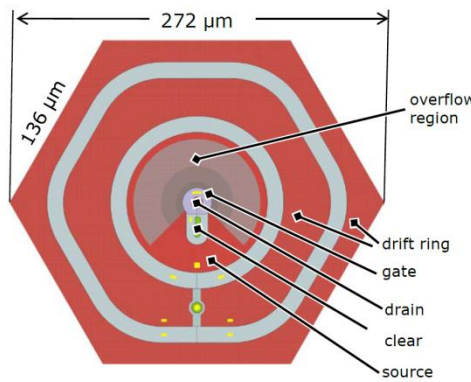
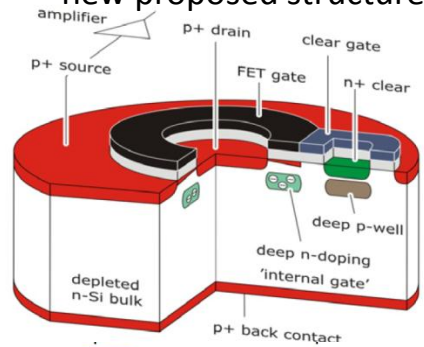
L. Andricek – MPI Halbleiterlabor, Munich

“DSSC – an X-ray Imager with Mega-Frame Readout Capabilities for the European XFEL”

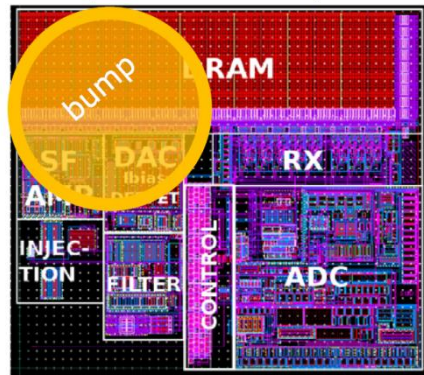
ILC-like beam structure:
 10 Hz train, 2700 e⁻/train,
 bunch spacing 220 ns
 → need 5 MHz frame
 rate with storage of >500
 frames/burst



- 1 Mpixel, 2D X-ray cameras at the end stations, energy range 0.5-25 keV, need to handle large dynamic range: new proposed structure with variable gain



- Hexagonal pixel, 204x236µm pitch
- 130nm readout ASIC with 8-bit ADC and SRAM in pixel



XFEL DSSC The European XFEL – DESY, Hamburg

XFEL facility – overall 3.4 km

- ▷ electron LINAC
 - Length: 1.6 km
 - Energy: 17.5 GeV (nominal)
- ▷ beam distribution stations
 - undulators (100 ... 200 m)
- ▷ 5 beam lines to the experiment stations

XFEL DSSC The DEPFET for the XFEL

DEPFET Sensor with Signal Compression - DSSC

Device Simulation

- The internal gate extends into the region below the source
- Small signals collected directly below the channel
 - ↳ Most effective, large signal
- Large signals spill over into the region below the source
 - ↳ Less effective, smaller signal
- staggered potential inside internal gate by varying impl. doses

Color coded Potential: positive (red) to negative (blue)